## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Appl. No.:10/695,336 Applicant(s): Geiss et al.

Filed.: October 28, 2003 Art Unit: 2813

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Title: METHOD OF CONTROLLING GRAIN SIZE IN A POLYSILICON LAYER AND

IN SEMICONDUCTOR DEVICES HAVING POLYSILICON STRUCTURES

Honorable Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

## **REQUEST FOR RECONSIDERATION**

This Request for Reconsideration is being filed in response to the Final Office Action mailed on January 29, 2007. Applicants request this Amendment be entered in the above-identified application and reconsideration of the application in view of the Amendments and Remarks that follow.